

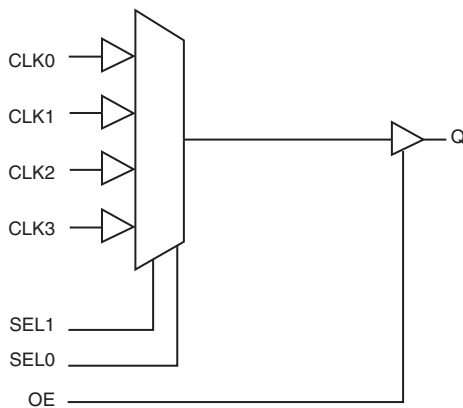
GENERAL DESCRIPTION

The 83054 is a low skew, 4:1, Single-ended Multiplexer and a member of the family of High Performance Clock Solutions from IDT. The 83054 has four selectable single-ended clock inputs and one single-ended clock output. The output has a V_{DDO} pin which may be set at 3.3V, 2.5V, or 1.8V, making the device ideal for use in voltage translation applications. An output enable pin places the output in a high impedance state which may be useful for testing or debug purposes. The device operates up to 250MHz and is packaged in a 16 TSSOP package.

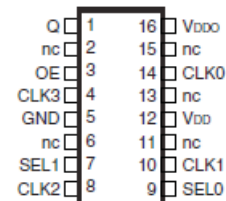
FEATURES

- 4:1 single-ended multiplexer
- Q nominal output impedance: 7Ω ($V_{DDO} = 3.3V$)
- Maximum output frequency: 250MHz
- Propagation delay: 3ns (maximum), $V_{DD} = V_{DDO} = 3.3V$
- Input skew: 225ps (maximum), $V_{DD} = V_{DDO} = 3.3V$
- Part-to-part skew: 780ps (maximum), $V_{DD} = V_{DDO} = 3.3V$
- Additive phase jitter, RMS: 0.19ps (typical), 3.3V/3.3V
- Operating supply modes:
 V_{DD}/V_{DDO}
 3.3V/3.3V
 3.3V/2.5V
 3.3V/1.8V
 2.5V/2.5V
 2.5V/1.8V
- -40°C to 85°C ambient operating temperature
- Available in lead-free (RoHS 6) package

BLOCK DIAGRAM



PIN ASSIGNMENT



83054
16-Lead TSSOP
 4.4mm x 5.0mm x 0.92mm package body
G Package
 Top View

TABLE 1. PIN DESCRIPTIONS

| Number | Name | Type | | Description |
|------------------|------------------------|--------|----------|---|
| 1 | Q | Output | | Single-ended clock output. LVCMOS/LVTTL interface levels. |
| 3 | OE | Input | Pullup | Output enable. When LOW, outputs are in HIGH impedance state. When HIGH, outputs are active. LVCMOS / LVTTL interface levels. |
| 4, 8, 10, 14 | CLK3, CLK2, CLK1, CLK0 | Input | Pulldown | Single-ended clock inputs. LVCMOS/LVTTL interface levels. |
| 5 | GND | Power | | Power supply ground. |
| 7, 9 | SEL1, SEL0 | Input | Pulldown | Clock select input. See Control Input Function Table. LVCMOS / LVTTL interface levels. |
| 2, 6, 11, 13, 15 | nc | Unused | | No connect. |
| 12 | V _{DD} | Power | | Power and input supply pin. |
| 16 | V _{DDO} | Power | | Output supply pin. |

NOTE: *Pullup* and *Pulldown* refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

TABLE 2. PIN CHARACTERISTICS

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------------------|--|-----------------|---------|---------|---------|-------|
| C _{IN} | Input Capacitance | | | 4 | | pF |
| R _{PULLUP} | Input Pullup Resistor | | | 51 | | kΩ |
| R _{PULLDOWN} | Input Pulldown Resistor | | | 51 | | kΩ |
| C _{PD} | Power Dissipation Capacitance (per output) | V = 3.465V | | 18 | | pF |
| | | V = 2.625V | | 20 | | pF |
| | | V = 1.89V | | 30 | | pF |
| R _{OUT} | Output Impedance | V = 3.465V | | 7 | | Ω |
| | | V = 2.625V | | 7 | | Ω |
| | | V = 1.89V | | 10 | | Ω |

TABLE 3. CONTROL INPUT FUNCTION TABLE

| Control Inputs | | Input Selected to Q |
|----------------|------|---------------------|
| SEL1 | SEL0 | |
| 0 | 0 | CLK0 |
| 0 | 1 | CLK1 |
| 1 | 0 | CLK2 |
| 1 | 1 | CLK3 |

ABSOLUTE MAXIMUM RATINGS

| | |
|--|---------------------------|
| Supply Voltage, V_{DD} | 4.6V |
| Inputs, V_I | -0.5V to $V_{DD} + 0.5V$ |
| Outputs, V_O | -0.5V to $V_{DDO} + 0.5V$ |
| Package Thermal Impedance, θ_{JA} | 89°C/W (0 lfm) |
| Storage Temperature, T_{STG} | -65°C to 150°C |

NOTE: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

TABLE 4A. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------|-----------------------|-----------------|---------|---------|---------|-------|
| V_{DD} | Power Supply Voltage | | 3.135 | 3.3 | 3.465 | V |
| V_{DDO} | Output Supply Voltage | | 3.135 | 3.3 | 3.465 | V |
| I_{DD} | Power Supply Current | | | | 40 | mA |
| I_{DDO} | Output Supply Current | | | | 5 | mA |

TABLE 4B. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $V_{DDO} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------|-----------------------|-----------------|---------|---------|---------|-------|
| V_{DD} | Power Supply Voltage | | 3.135 | 3.3 | 3.465 | V |
| V_{DDO} | Output Supply Voltage | | 2.375 | 2.5 | 2.625 | V |
| I_{DD} | Power Supply Current | | | | 40 | mA |
| I_{DDO} | Output Supply Current | | | | 5 | mA |

TABLE 4C. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $V_{DDO} = 1.8V \pm 0.2V$, $T_A = -40^\circ\text{C}$ TO 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------|-----------------------|-----------------|---------|---------|---------|-------|
| V_{DD} | Power Supply Voltage | | 3.135 | 3.3 | 3.465 | V |
| V_{DDO} | Output Supply Voltage | | 1.71 | 1.8 | 1.89 | V |
| I_{DD} | Power Supply Current | | | | 40 | mA |
| I_{DDO} | Output Supply Current | | | | 5 | mA |

TABLE 4D. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = V_{DDO} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------|-----------------------|-----------------|---------|---------|---------|-------|
| V_{DD} | Power Supply Voltage | | 2.375 | 2.5 | 2.625 | V |
| V_{DDO} | Output Supply Voltage | | 2.375 | 2.5 | 2.625 | V |
| I_{DD} | Power Supply Current | | | | 35 | mA |
| I_{DDO} | Output Supply Current | | | | 5 | mA |

TABLE 4E. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = 2.5V \pm 5\%$, $V_{DDO} = 1.8V \pm 0.2V$, $T_A = -40^\circ\text{C}$ TO 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------|-----------------------|-----------------|---------|---------|---------|-------|
| V_{DD} | Power Supply Voltage | | 2.375 | 2.5 | 2.625 | V |
| V_{DDO} | Output Supply Voltage | | 1.71 | 1.8 | 1.89 | V |
| I_{DD} | Power Supply Current | | | | 35 | mA |
| I_{DDO} | Output Supply Current | | | | 5 | mA |

TABLE 4F. LVC MOS/LVTTL DC CHARACTERISTICS, $T_A = -40^{\circ}\text{C}$ TO 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|----------|---------------------|--|---|---------|----------------|---------------|
| V_{IH} | Input High Voltage | $V_{DD} = 3.3\text{V} \pm 5\%$ | 2 | | $V_{DD} + 0.3$ | V |
| | | $V_{DD} = 2.5\text{V} \pm 5\%$ | 1.7 | | $V_{DD} + 0.3$ | V |
| V_{IL} | Input Low Voltage | $V_{DD} = 3.3\text{V} \pm 5\%$ | -0.3 | | 0.8 | V |
| | | $V_{DD} = 2.5\text{V} \pm 5\%$ | -0.3 | | 0.7 | V |
| I_{IH} | Input High Current | CLK0:CLK3, SEL0, SEL1 | $V_{DD} = 3.3\text{V}$ or $2.5\text{V} \pm 5\%$ | | 150 | μA |
| | | OE | $V_{DD} = 3.3\text{V}$ or $2.5\text{V} \pm 5\%$ | | 5 | μA |
| I_{IL} | Input Low Current | CLK0:CLK3, SEL0, SEL1 | $V_{DD} = 3.3\text{V}$ or $2.5\text{V} \pm 5\%$ | -5 | | μA |
| | | OE | $V_{DD} = 3.3\text{V}$ or $2.5\text{V} \pm 5\%$ | -150 | | μA |
| V_{OH} | Output High Voltage | $V_{DDO} = 3.3\text{V} \pm 5\%$; NOTE 1 | 2.6 | | | V |
| | | $V_{DDO} = 2.5\text{V} \pm 5\%$; NOTE 1 | 1.8 | | | V |
| | | $V_{DDO} = 1.8\text{V} \pm 5\%$; NOTE 1 | $V_{DD} - 0.3$ | | | V |
| V_{OL} | Output Low Voltage | $V_{DDO} = 3.3\text{V} \pm 5\%$; NOTE 1 | | | 0.5 | V |
| | | $V_{DDO} = 2.5\text{V} \pm 5\%$; NOTE 1 | | | 0.45 | V |
| | | $V_{DDO} = 1.8\text{V} \pm 5\%$; NOTE 1 | | | 0.35 | V |

NOTE 1: Outputs terminated with 50Ω to $V_{DDO}/2$. See Parameter Measurement section, "Load Test Circuit" diagrams.

TABLE 5A. AC CHARACTERISTICS, $V_{DD} = V_{DDO} = 3.3\text{V} \pm 5\%$, $T_A = -40^{\circ}\text{C}$ TO 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|--------------|---|-----------------------------|---------|---------|---------|-------|
| f_{MAX} | Output Frequency | | | | 250 | MHz |
| $t_{p_{LH}}$ | Propagation Delay, Low to High; NOTE 1 | | 2.4 | 2.7 | 3.0 | ns |
| $t_{p_{HL}}$ | Propagation Delay, High to Low; NOTE 1 | | 2.5 | 2.7 | 2.9 | ns |
| $t_{sk(i)}$ | Input Skew; NOTE 2 | | | 55 | 225 | ps |
| t_{jit} | Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section; NOTE 3 | 155.52MHz, (12kHz to 20MHz) | | 0.19 | | ps |
| $t_{sk(pp)}$ | Part-to-Part Skew; NOTE 2, 4 | | | | 780 | ps |
| t_R / t_F | Output Rise/Fall Time | 20% to 80% | 50 | | 500 | ps |
| odc | Output Duty Cycle | | 45 | | 55 | % |
| MUX_{ISOL} | MUX Isolation | @ 100MHz | | 45 | | dB |

NOTE 1: Measured from $V_{DD}/2$ of the input to $V_{DDO}/2$ of the output.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Driving only one input clock.

NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of input on each device, the output is measured at $V_{DDO}/2$.

TABLE 5B. AC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $V_{DDO} = 2.5V \pm 5\%$, $T_A = -40^\circ C$ TO $85^\circ C$

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|--------------|---|--------------------------------|---------|---------|---------|-------|
| f_{MAX} | Output Frequency | | | | 250 | MHz |
| tp_{LH} | Propagation Delay, Low to High; NOTE 1 | | 2.5 | 2.8 | 3.1 | ns |
| tp_{HL} | Propagation Delay, High to Low; NOTE 1 | | 2.6 | 2.8 | 3.0 | ns |
| $t_{sk(i)}$ | Input Skew; NOTE 2 | | | 45 | 150 | ps |
| f_{jit} | Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section; NOTE 3 | 155.52MHz, (12kHz to 20MHz) | | 0.14 | | ps |
| $t_{sk(pp)}$ | Part-to-Part Skew; NOTE 2, 4 | | | | 780 | ps |
| t_R / t_F | Output Rise/Fall Time | 20% to 80% | 50 | | 500 | ps |
| odc | Output Duty Cycle | | 45 | | 55 | % |
| MUX_{ISOL} | MUX Isolation | @ 100MHz | | 45 | | dB |

NOTE 1: Measured from $V_{DD}/2$ of the input to $V_{DDO}/2$ of the output.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Driving only one input clock.

NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of input on each device, the output is measured at $V_{DDO}/2$.

TABLE 5C. AC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $V_{DDO} = 1.8V \pm 5\%$, $T_A = -40^\circ C$ TO $85^\circ C$

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|--------------|---|--------------------------------|---------|---------|---------|-------|
| f_{MAX} | Output Frequency | | | | 250 | MHz |
| tp_{LH} | Propagation Delay, Low to High; NOTE 1 | | 2.7 | 3.2 | 3.8 | ns |
| tp_{HL} | Propagation Delay, High to Low; NOTE 1 | | 2.8 | 3.3 | 3.8 | ns |
| $t_{sk(i)}$ | Input Skew; NOTE 2 | | | 50 | 150 | ps |
| f_{jit} | Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section; NOTE 3 | 155.52MHz, (12kHz to 20MHz) | | 0.16 | | ps |
| $t_{sk(pp)}$ | Part-to-Part Skew; NOTE 2, 4 | | | | 780 | ps |
| t_R / t_F | Output Rise/Fall Time | 20% to 80% | 100 | | 700 | ps |
| odc | Output Duty Cycle | | 45 | | 55 | % |
| MUX_{ISOL} | MUX Isolation | @ 100MHz | | 45 | | dB |

NOTE 1: Measured from $V_{DD}/2$ of the input to $V_{DDO}/2$ of the output.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Driving only one input clock.

NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of input on each device, the output is measured at $V_{DDO}/2$.

TABLE 5D. AC CHARACTERISTICS, $V_{DD} = V_{DDO} = 2.5V \pm 5\%$, $T_A = -40^\circ C$ TO $85^\circ C$

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|--------------|---|--------------------------------|---------|---------|---------|-------|
| f_{MAX} | Output Frequency | | | | 250 | MHz |
| tp_{LH} | Propagation Delay, Low to High; NOTE 1 | | 2.5 | 3.0 | 3.5 | ns |
| tp_{HL} | Propagation Delay, High to Low; NOTE 1 | | 2.5 | 2.9 | 3.4 | ns |
| $tsk(i)$ | Input Skew; NOTE 2 | | | 60 | 175 | ps |
| $tjit$ | Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section; NOTE 3 | 155.52MHz, (12kHz to 20MHz) | | 0.21 | | ps |
| $tsk(pp)$ | Part-to-Part Skew; NOTE 2, 4 | | | | 780 | ps |
| t_R / t_F | Output Rise/Fall Time | 20% to 80% | 100 | | 500 | ps |
| odc | Output Duty Cycle | | 40 | | 60 | % |
| MUX_{ISOL} | MUX Isolation | @ 100MHz | | 45 | | dB |

NOTE 1: Measured from $V_{DD}/2$ of the input to $V_{DDO}/2$ of the output.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Driving only one input clock.

NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of input on each device, the output is measured at $V_{DDO}/2$.

TABLE 5E. AC CHARACTERISTICS, $V_{DD} = 2.5V \pm 5\%$, $V_{DDO} = 1.8V \pm 5\%$, $T_A = -40^\circ C$ TO $85^\circ C$

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|--------------|---|--------------------------------|---------|---------|---------|-------|
| f_{MAX} | Output Frequency | | | | 250 | MHz |
| tp_{LH} | Propagation Delay, Low to High; NOTE 1 | | 2.6 | 3.3 | 4.0 | ns |
| tp_{HL} | Propagation Delay, High to Low; NOTE 1 | | 2.7 | 3.3 | 4.0 | ns |
| $tsk(i)$ | Input Skew; NOTE 2 | | | 50 | 150 | ps |
| $tjit$ | Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section; NOTE 3 | 155.52MHz, (12kHz to 20MHz) | | 0.17 | | ps |
| $tsk(pp)$ | Part-to-Part Skew; NOTE 2, 4 | | | | 780 | ps |
| t_R / t_F | Output Rise/Fall Time | 20% to 80% | 100 | | 700 | ps |
| odc | Output Duty Cycle | | 40 | | 60 | % |
| MUX_{ISOL} | MUX Isolation | @ 100MHz | | 45 | | dB |

NOTE 1: Measured from $V_{DD}/2$ of the input to $V_{DDO}/2$ of the output.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

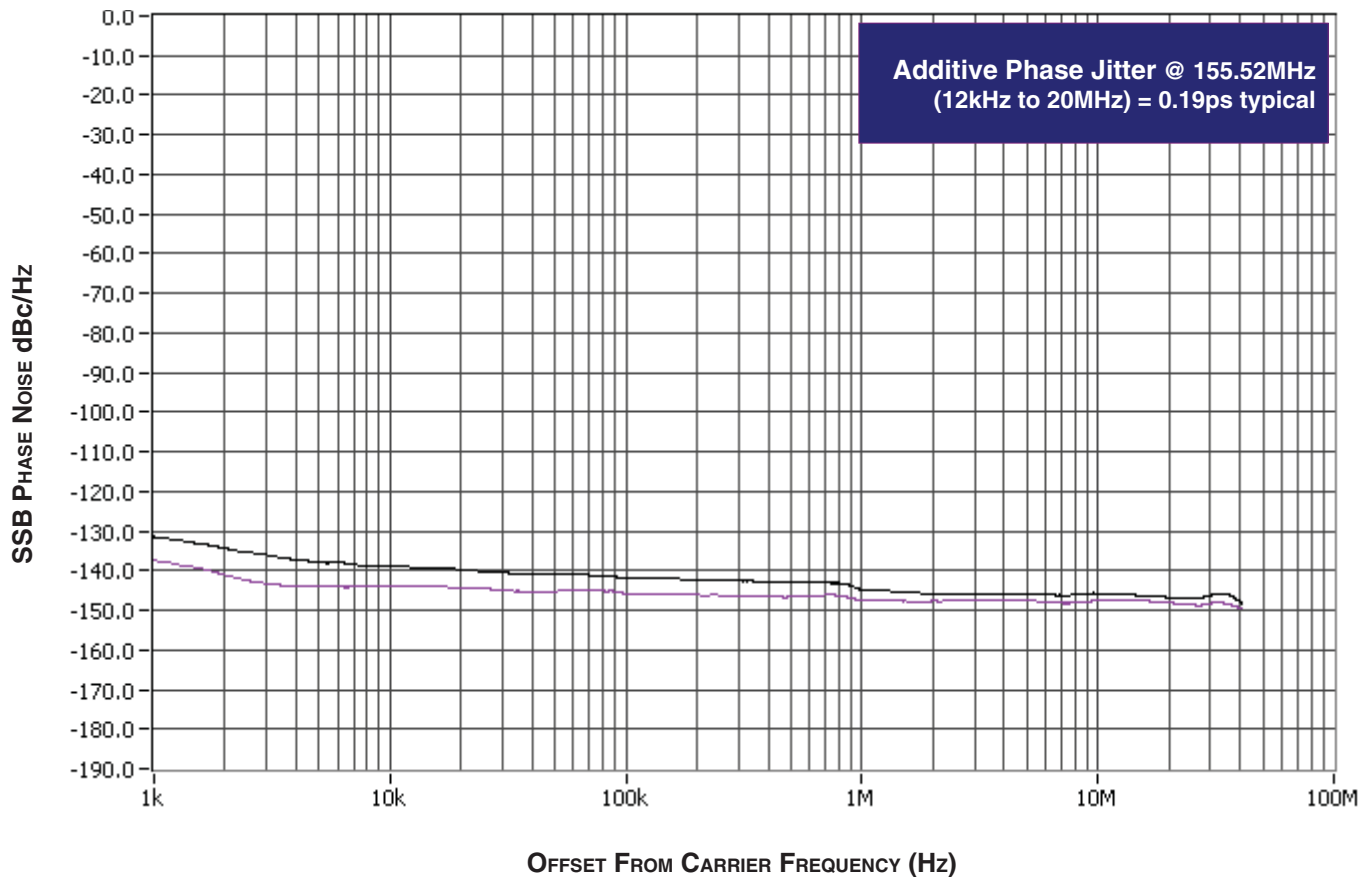
NOTE 3: Driving only one input clock.

NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of input on each device, the output is measured at $V_{DDO}/2$.

ADDITIVE PHASE JITTER

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the ***dBc Phase Noise***. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio of the power in the 1Hz band to the power in the

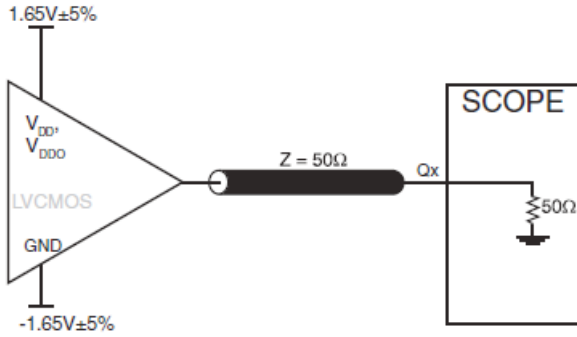
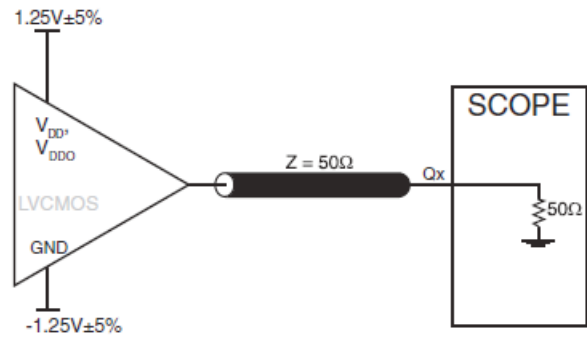
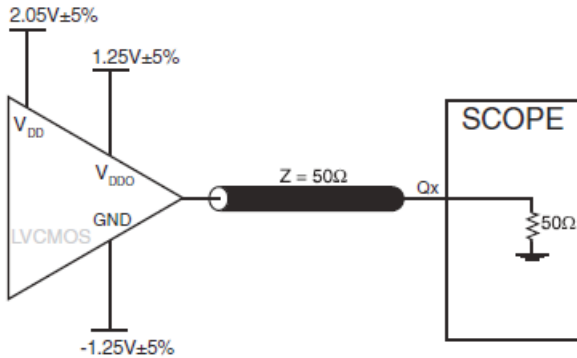
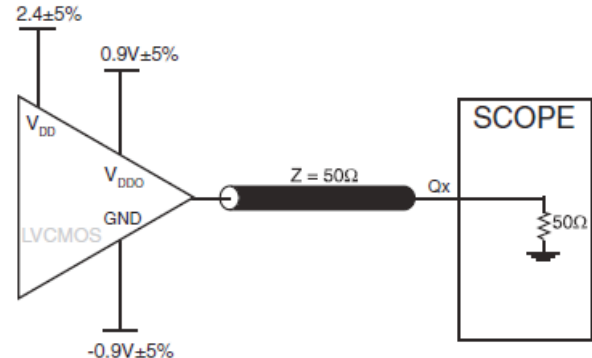
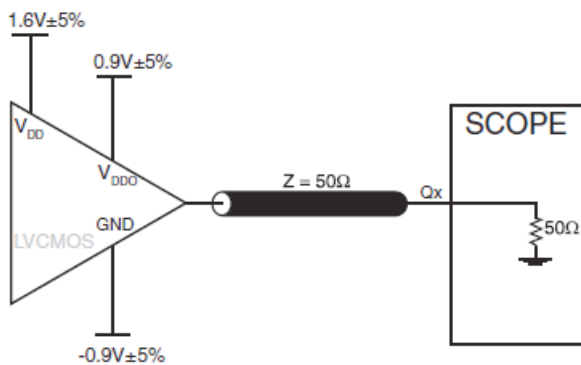
fundamental. When the required offset is specified, the phase noise is called a ***dBc*** value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application, we get a better understanding of its effects on the desired application. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.



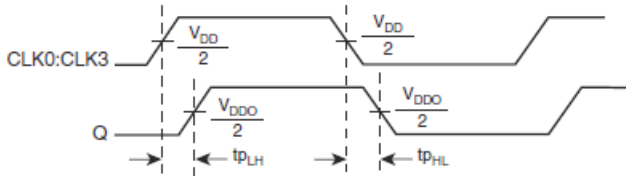
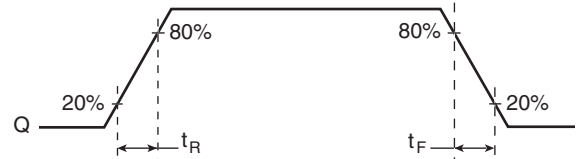
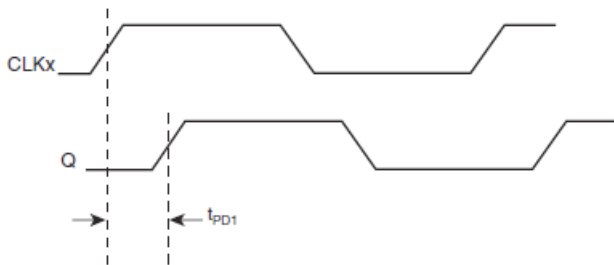
As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the device.

This is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.

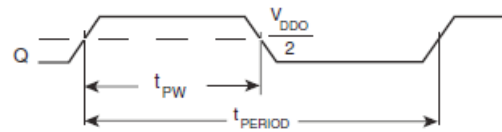
PARAMETER MEASUREMENT INFORMATION


3.3V CORE/3.3V OUTPUT LOAD AC TEST CIRCUIT

2.5V CORE/2.5V OUTPUT LOAD AC TEST CIRCUIT

3.3V CORE/2.5V OUTPUT LOAD AC TEST CIRCUIT

3.3V CORE/1.8V OUTPUT LOAD AC TEST CIRCUIT

2.5 CORE/1.8V OUTPUT LOAD AC TEST CIRCUIT

PART-TO-PART SKEW


PROPAGATION DELAY

OUTPUT RISE/FALL TIME

INPUT SKEW

$$tsk(i) = |t_{PD2} - t_{PD1}|$$



$$odc = \frac{t_{PW}}{t_{PERIOD}} \times 100\%$$

OUTPUT DUTY CYCLE/PULSE WIDTH/PERIOD

APPLICATION INFORMATION

RECOMMENDATIONS FOR UNUSED INPUT PINS

INPUTS:

CLK INPUTS

For applications not requiring the use of a clock input, it can be left floating. Though not required, but for additional protection, a 1k Ω resistor can be tied from the CLK input to ground.

LVC MOS CONTROL PINS

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A 1k Ω resistor can be used.

RELIABILITY INFORMATION

TABLE 6. θ_{JA} VS. AIR FLOW TABLE FOR 16 LEAD TSSOP

| θ_{JA} by Velocity (Linear Feet per Minute) | | | |
|--|-----------|-----------|-----------|
| | 0 | 200 | 500 |
| Single-Layer PCB, JEDEC Standard Test Boards | 137.1°C/W | 118.2°C/W | 106.8°C/W |
| Multi-Layer PCB, JEDEC Standard Test Boards | 89.0°C/W | 81.8°C/W | 78.1°C/W |

NOTE: Most modern PCB designs use multi-layered boards. The data in the second row pertains to most designs.

TRANSISTOR COUNT

The transistor count for 83054 is: 874

PACKAGE OUTLINE AND PACKAGE DIMENSIONS

PACKAGE OUTLINE - G SUFFIX FOR 16 LEAD TSSOP

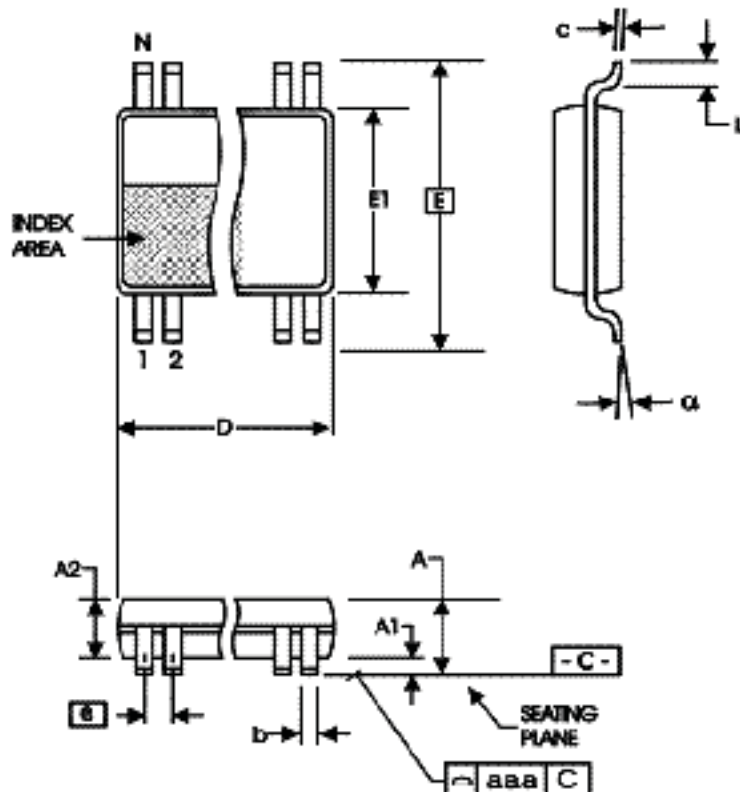


TABLE 7. PACKAGE DIMENSIONS

| SYMBOL | Millimeters | |
|----------|-------------|---------|
| | Minimum | Maximum |
| N | 16 | |
| A | -- | 1.20 |
| A1 | 0.05 | 0.15 |
| A2 | 0.80 | 1.05 |
| b | 0.19 | 0.30 |
| c | 0.09 | 0.20 |
| D | 4.90 | 5.10 |
| E | 6.40 BASIC | |
| E1 | 4.30 | 4.50 |
| e | 0.65 BASIC | |
| L | 0.45 | 0.75 |
| α | 0° | 8° |
| aaa | -- | 0.10 |

Reference Document: JEDEC Publication 95, MO-153

TABLE 8. ORDERING INFORMATION

| Part/Order Number | Marking | Package | Shipping Packaging | Temperature |
|--------------------------|----------------|---------------------------|---------------------------|--------------------|
| 83054AGILF | 83054AIL | 16 Lead "Lead-Free" TSSOP | tube | -40°C to 85°C |
| 83054AGILFT | 83054AIL | 16 Lead "Lead-Free" TSSOP | tape & reel | -40°C to 85°C |

| REVISION HISTORY SHEET | | | | |
|------------------------|-----------|-----------------|--|----------|
| Rev | Table | Page | Description of Change | Date |
| A | T8 | 12 | Ordering Information Table - corrected Part/Order Numbers. | 1/3/06 |
| B | T5A - T5E | 1 4 - 6 7 | Features Section - added Additive Phase Jitter bullet. AC Characteristics Tables - added tjit row and spec. Added Additive Phase Jitter section. | 01/04/07 |
| C | T5A - T5E | 4 - 6 | AC Characteristics Tables - changed part-to-part skew specs. | 03/07/08 |
| C | T8 | 12 | Ordering Information - removed leaded devices. Updated data sheet format. | 3/20/15 |
| C | T8 | 1 12 | General Description - Removed HiPerClockS. Ordering Information - removed LF note below the table. Updated header and footer. | 12/15/15 |



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